

# 3D scanning by means of dual-projector structured light illumination

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## ABSTRACT

This document shows the desired format and appearance of a manuscript prepared for the Proceedings of the SPIE. It contains general formatting instructions and hints about how to use LaTeX. The LaTeX source file that produced this document, `article.tex` (Version 3.3), provides a template, used in conjunction with `spie.cls` (Version 3.3).

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## 1. INTRODUCTION

As one of the non-contact 3D shape measurement techniques, the structured light illumination (SLI) has been known for its high resolution and high speed.<sup>1</sup> Conventional SLI systems consist of one projector, one camera and one processing unit which is usually a computer. The projector presents patterns that are encoded with some information related to the pixel locations on the object to be measured. If the projection is on a flat surface, the patterns seen should be identical to its original design. However, with the presence of the non-planar object under the projection, what is actually seen from the camera is the distorted patterns on the surface of the object. By comparing and analyzing the distortion in the images taken by the camera, the 3D surface of the object can eventually be reconstructed in a processing unit.

Within the scope of this fundamental idea and system structure, a lot of research has been done over the past several decades.<sup>2</sup> Different practical implementations have been proposed, from pattern design to system calibration, then to the algorithms that are used to decode the captured patterns. One widely studied area is the one-shot SLI strategy in which only one static pattern is projected onto the object. It employs color pattern,<sup>3</sup> binary grid pattern,<sup>4</sup> gray-scale pattern<sup>5</sup> or even composite pattern.<sup>6</sup> Since there is only one image need to be processed for a scan, the 3D reconstruction can be completed fast. The one-shot strategy is ideal for high speed applications such as real time scanning. But in terms of accuracy, it is not so promising compared to some multi-shot SLI strategy in which the 3D reconstruction is derived by projecting a sequence of patterns and processing multiple images.<sup>7</sup>

According to the method of encoding the information containing the pixel location into the pattern, phase measuring profilometry (PMP)<sup>8</sup> is a subset of SLI techniques that acquires the depth value by translating the phase data from the projected patterns pixelwise. The PMP has some advantageous features including its insensitivity to ambient light and its high accuracy.<sup>9,10</sup> Higher frequency patterns have been introduced to PMP systems to reduce the effects of the noise and achieve higher accuracy.<sup>11</sup> Nonetheless, higher frequency patterns also produces the phase ambiguity which requires the system to execute some extra computation called phase unwrapping.<sup>12</sup> Furthermore, adding high frequency patterns increases the projection time as well as the number of images to be processed, which accordingly decreases the overall speed of the system. Liu *et al.* proposed an ingenious dual-frequency pattern strategy which combines a high-frequency pattern and a unit-frequency pattern into one composite pattern,<sup>13</sup> it improved the accuracy without increasing the scanning time.

In this paper, we propose a dual-projector, dual-frequency SLI scheme and its practical implementation. Provided with a wider projection angle by two projectors, our system not only takes advantage of the Liu *et al.*'s pattern design, but also overcomes the issues like multi-path<sup>14</sup> and occlusion<sup>15</sup> that single-projector systems

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suffer from. Additionally, if two projectors are positioned side by side and aimed at the same projection area, we can get double the luminance. For instance, suppose the projectors we use are two identical Optoma ML750ST which has around 500 lumens each,<sup>16</sup> by using two projectors, we obtain a total 1000 lumens. Higher light intensity gives rise to the higher signal-to-noise ratio (SNR),<sup>17</sup> which makes the system less susceptible to noise, consequently the system becomes more robust and accurate.

## 2. DUAL-FREQUENCY PHASE MEASURING PROFILOMETRY

The dual-frequency pattern scheme was initially proposed by Liu *et al.*,<sup>13</sup> it is essentially an improved derivation of the phase measuring profilometry.<sup>10</sup> In the traditional PMP a series of phase-shifting sinusoidal fringe patterns are projected onto the object to be measured, the fringe patterns can be either horizontal or vertical, the presence of the object distorts the patterns, then by analyzing the phase values in the deformed pattern images, the 3D depth values can be obtained.

Suppose the phase-shifting patterns are vertical, which indicates that all the pixels in a same row have the identical intensity, and from top to bottom the value of intensities in each row form a sinusoidal function. Therefore, this kind of PMP patterns can be generalized as:

$$I_n^p(x^p, y^p) = A^p + B^p \cos(2\pi f y^p - \frac{2\pi n}{N}), \quad (1)$$

where  $I_n^p$  is the intensity of the pixel at the coordinate  $(x^p, y^p)$  from the projector's point of view;  $A^p$  is background intensity which is considered as a constant;  $B^p$  is another constant which represents the fringe contrast compared to the background;  $f$  is the frequency of the fringe pattern set which is equal to the number of sinusoidal periods from top to the bottom of the projected patterns;  $N$  is the total number of the phase-shifting patterns of the same frequency in a set,  $n$  is the current number of the pattern within the range of  $[0, N - 1]$ .

On the camera's side, the image of the object under the projection of each unique PMP pattern is captured as part of the data to reconstruct the 3D profile of the object. So the projected scene of the object can be described as eq. (2) from the camera's point of view,

$$I_n^c(x^c, y^c) = A^c(x^c, y^c) + B^c(x^c, y^c) \cos(\phi(x^c, y^c) - \frac{2\pi n}{N}), \quad (2)$$

where  $I_n^c$  is the intensity of the given pixel  $(x^c, y^c)$  in the camera's coordinates system;  $A^c(x^c, y^c)$  is the average intensity of the given pixel over the  $N$  patterns;  $B^c$  can be considered as the average intensity of the PMP pattern seen by the camera, so for any given pixel  $(x^c, y^c)$  in a pattern set  $[0, N - 1]$ ,  $A^c$  and  $B^c$  are both constant, furthermore,  $B^c(x^c, y^c)$  can be derived from eq. (2) as:

$$B^c(x^c, y^c) = \frac{2}{N} \sqrt{\left[ \sum_{n=0}^{N-1} I_n^c(x^c, y^c) \sin(\frac{2\pi n}{N}) \right]^2 + \left[ \sum_{n=0}^{N-1} I_n^c(x^c, y^c) \cos(\frac{2\pi n}{N}) \right]^2}. \quad (3)$$

In Equation 2, there is another important constant  $\phi$  for any given pixel  $(x^c, y^c)$  in a given pattern set  $[0, N - 1]$ , it is the phase value  $\phi(x^c, y^c)$  of the distorted fringe patterns that is eventually used to calculate the corresponding depth value of the object. The expression of  $\phi(x^c, y^c)$  can be inferred from eq. (3) as:

$$\phi(x^c, y^c) = \arctan \frac{\sum_{n=0}^{N-1} I_n^c(x^c, y^c) \sin(\frac{2\pi n}{N})}{\sum_{n=0}^{N-1} I_n^c(x^c, y^c) \cos(\frac{2\pi n}{N})}. \quad (4)$$

The dual-frequency pattern scheme adds a second sinusoidal component to the phase-shifting patterns, as a result, the total number of patterns is still  $N$ , but each pattern has two sinusoidal components, one is of unit frequency  $f_u$ , the other is of a high frequency  $f_h$  that is used to reduce the impact of noises in the system. If we extend the single-frequency PMP pattern above to the dual-frequency, the intensities of the row pixels from top to bottom would be like an amplitude modulation in which the  $f_u$  is frequency of the modulating signal

and  $f_h$  is the frequency of the carrier wave. According to Liu *et al.*, from the projector's point of view, the new dual-frequency pattern is expressed as:

$$I_n^p(x^p, y^p) = A^p + B_1^p \cos(2\pi f_h y^p - \frac{2\pi n}{N}) + B_2^p \cos(2\pi f_u y^p - \frac{4\pi n}{N}), \quad (5)$$

where the  $I_n^p$  is the intensity of the pixel  $(x^p, y^p)$  in the  $n^{th}$  pattern. Similarly the intensity equation of the camera coordinates used for reconstruction becomes:

$$I_n^c(x^c, y^c) = A^c(x^c, y^c) + B_1^c(x^c, y^c) \cos(\phi_h(x^c, y^c) - \frac{2\pi n}{N}) + B_2^c(x^c, y^c) \cos(\phi_u(x^c, y^c) - \frac{4\pi n}{N}). \quad (6)$$

Likewise the  $B_1^c$ ,  $B_2^c$  and  $\phi_h$ ,  $\phi_u$  can be derived from eq. (3) and eq. (4) respectively,

$$B_m^c(x^c, y^c) = \frac{2}{N} \sqrt{[\sum_{n=0}^{N-1} I_n^c(x^c, y^c) \sin(m \frac{2\pi n}{N})]^2 + [\sum_{n=0}^{N-1} I_n^c(x^c, y^c) \cos(m \frac{2\pi n}{N})]^2}, \quad (7)$$

where  $m = 1$  or  $2$  in this case,

$$\phi_h(x^c, y^c) = \arctan \frac{\sum_{n=0}^{N-1} I_n^c(x^c, y^c) \sin(\frac{2\pi n}{N})}{\sum_{n=0}^{N-1} I_n^c(x^c, y^c) \cos(\frac{2\pi n}{N})}, \quad (8)$$

$$\phi_u(x^c, y^c) = \arctan \frac{\sum_{n=0}^{N-1} I_n^c(x^c, y^c) \sin(\frac{4\pi n}{N})}{\sum_{n=0}^{N-1} I_n^c(x^c, y^c) \cos(\frac{4\pi n}{N})}. \quad (9)$$

In eq. (8) and (9),  $\phi_h$  and  $\phi_u$  are confined within  $[-\pi, \pi]$ , however, the actual range of  $\phi_h$  is  $[0, 2f_h\pi]$ , the  $\phi_h$  is called the wrapped phase. Unwrapping the  $\phi_h$  to  $\phi_h \in [0, 2f_h\pi]$  can lead to a more accurate conversion from phase to depth. In order to obtain  $\phi_h$ , the value of  $\phi_u$  is used as the following equation shows,

$$\tilde{\phi}_h = \phi_h + 2\pi \lfloor \frac{\phi_u}{2\pi/f_h} \rfloor, \quad (10)$$

where the  $\lfloor \cdot \rfloor$  is the symbol of floor function which outputs the greatest integer less than or equal to the value enclosed.

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## 3. DUAL-PROJECTOR PHASE MEASURING PROFILOMETRY

Our FPGA-based dual-projector Structured Light Illumination (SLI) system generates two synchronized SLI patterns which are then fed to two projectors via HDMI. Meanwhile, the projectors and the camera need to be synchronized to ensure that the camera images are taken at the right timing. The system diagram is shown in Figure 1. The two SLI pattern generators output two synchronized phase-shifting fringe patterns which are later encoded into TMDS data streams by the HDMI transmitters and eventually move to projectors.

HDMI is the abbreviation of High-Definition Multimedia Interface, it is one of the most popular display interfaces. The newest release, HDMI Version 2.1 supports up to  $10K$  video at  $120Hz$ . A standard HDMI connector has 19 pins as listed in Table 1. Data channel 2, 1, 0 are mainly used to transfer red, green and blue components of the video respectively. The HDMI does not only transfer video data, but also some auxiliary data, for example audio data, packet header. The auxiliary data, video data as well as some control signals are encoded in data channel 2, 1, 0 and then digitally transmitted in serial. In between any two adjacent video periods, one or more data island period and control period are inserted.



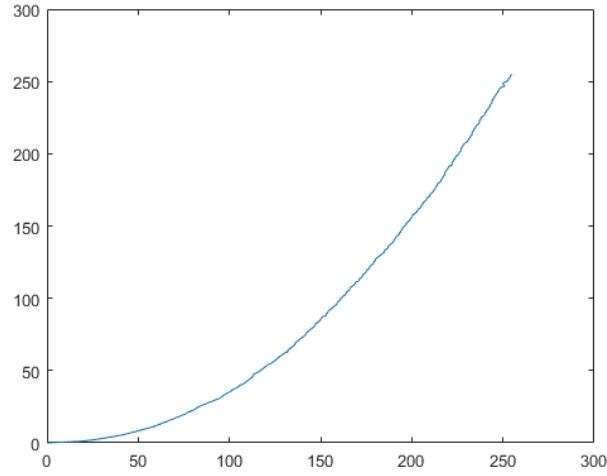


Figure 2: Non-linearity of the projector Optoma ML750ST

line as a differential signal to establish a high speed Ethernet communication.

The camera synchronization module controls the timing of the camera trigger signal, it detects the end of the camera's exposure time and makes sure that during the whole camera's exposure time, there is no different pattern projected and every unique phase-shifting fringe pattern is pictured sequentially by the camera. The projector in our SLI system operates at the resolution of  $800 \times 600$  and the refresh rate of  $120Hz$ . According to the document from VESA,<sup>18</sup> the HDMI timing should be set as Table 2 lists.

To obtain the uncommon  $73.25MHz$  pixel clock, we utilize a programmable oscillator Si514. By configuring the internal registers through  $I^2C$  bus, Si514 can generate any frequency from  $100kHz$  to  $250MHz$  with a tuning resolution of  $0.026$  ppb. Therefore, an  $I^2C$  master controller was incorporated into the system. One last module in the system is a lookup table (LUT) that is used to linearize the output of the projector. Ideally, the input digital values of the projector is proportional to the light intensity at the output side of the projector. The light intensity is measured by reading the pixel value of the photo taken by the camera. However, in practice, they are non-linear for most of the times due to some intrinsic characteristics of the projector, e. g. gamma distortion.<sup>19</sup> Applying a LUT to compensate the non-linearity is an effective way to address this problem, as shown in the Figure 2, the x-axis represents the 8-bit input digital value of the projector at a certain point of the scene, the y-axis represents the light intensity of the same point that is measured from camera's perspective.

This LUT can be hard-coded into the configuration file of the FPGA, but the drawback is that once the lookup table changes, the FPGA configuration file has to be changed. It is quite inconvenient especially when the system needs to be often applied to a different projector, because generating a new FPGA configuration file requires special software tool and takes more time. We devise a method that the user stores the LUT in an separate EEPROM chip which can be erased and written by any computer via some general serial or USB tools, and the SPI master module in the FPGA reads the EEPROM every time the system is powered on. With this approach, users can load new LUTs much faster and easier.

Figure 3 shows a picture of our tested system.

Table 2: HDMI timing of  $800 \times 600$  at  $120$  Hz

<b>Pixel Clock</b>	73.250MHz
<b>Hor. Front Porch</b>	48 pixels
<b>Hor. Sync Time</b>	32 pixels
<b>Hor. Back Porch</b>	80 pixels

<b>Ver. Front Porch</b>	3 lines
<b>Ver. Sync Time</b>	4 lines
<b>Ver. Back Porch</b>	29 lines

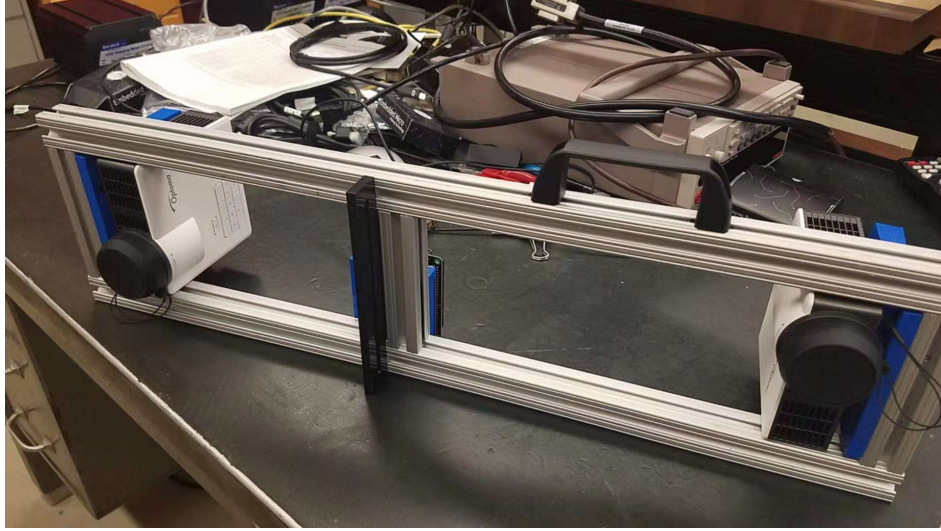


Figure 3: the dual-projector SLI system

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